

Notice of References Cited	Application/Control No. 10/661,983		Applicant(s)/Patent Under Reexamination WILDER ET AL.	
	Examiner Christian E. Rendón		Art Unit 3714	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2003/0176214	09-2003	Burak et al.	463/20
*	B	US-4,101,210	07-1978	Lo et al.	353/7
*	C	US-6,574,047	06-2003	Hawver, Jeffery R.	359/626
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Cees van Berkel and John A Clarke. "Characterization & Optimization of 3D-LCD Module Design" Feb 11-14 1997, SPIE International Conference on Electronic Imaging.
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.